MSG33001

SiGe HBT type

For low-noise RF amplifier

■ Features

- Compatible between high breakdown voltage and high cutoff frequency
- Low-noise, high-gain amplification
- Suitable for high-density mounting and downsizing of the equipment for Ultraminiature package

 $0.8 \text{ mm} \times 1.2 \text{ mm} \text{ (height } 0.52 \text{ mm)}$

■ Absolute Maximum Ratings $T_a = 25$ °C

Parameter	Symbol	Rating	Unit	
Collector-base voltage (Emitter open)	V _{CBO}	9	V	
Collector-emitter voltage (Base open)	V _{CEO}	6	V	
Emitter-base voltage (Collector open)	V_{EBO}	1	V	
Collector current	I_C	30	mA	
Collector power dissipation *	P_{C}	100	mW	
Junction temperature	T_{j}	125	°C	
Storage temperature	T _{stg}	-55 to +125	°C	

Note) *: Copper plate at the collector is 5.0 mm^2 on substrate at $10 \text{ mm} \times 12 \text{ mm} \times 0.8 \text{ mm}$.

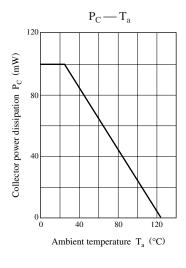
Unit: mm 0.33^{10.05} 3 0.23^{10.05} 12 0.23^{10.05} 12 0.23^{10.05} 1.20_{10.05} 1.20_{10.05}

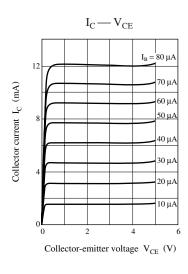
Marking Symbol: 5S

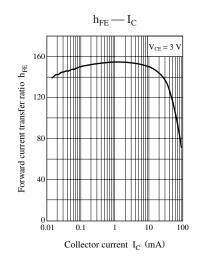
\blacksquare Electrical Characteristics $T_a = 25 ^{\circ}C \pm 3 ^{\circ}C$

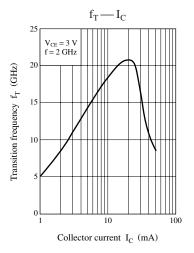
Parameter	Symbol	Conditions	Min	Тур	Max	Unit
Collector-base cutoff current (Emitter open)	I_{CBO}	$V_{CB} = 9 \text{ V}, I_{E} = 0$			1	nA
Collector-emitter cutoff current (Base open)	I _{CEO}	$V_{CE} = 6 \text{ V}, I_{B} = 0$			1	μΑ
Emitter-base cutoff current (Collector open)	I_{EBO}	$V_{EB} = 1 \text{ V}, I_C = 0$			1	μΑ
Forward current transfer ratio	h _{FE}	$V_{CE} = 3 \text{ V}, I_{C} = 3 \text{ mA}$	100		220	_
Transition frequency	f_T	$V_{CE} = 3 \text{ V}, I_{C} = 10 \text{ mA}, f = 2 \text{ GHz}$		19		GHz
Forward transfer gain	S _{21e} 2	$V_{CE} = 3 \text{ V}, I_{C} = 10 \text{ mA}, f = 2 \text{ GHz}$	9.0	11.0		dB
Noise figure	NF	$V_{CE} = 3 \text{ V}, I_{C} = 3 \text{ mA}, f = 2 \text{ GHz}$		1.4	2.0	dB
Collector output capacitance	C _{ob}	$V_{CB} = 3 \text{ V}, I_{E} = 0, f = 1 \text{ MHz}$		0.3	0.6	pF
(Common base, input open circuited)						

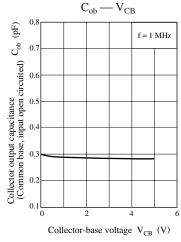
Note) Measuring methods are based on JAPANESE INDUSTRIAL STANDARD JIS C 7030 measuring methods for transistors.

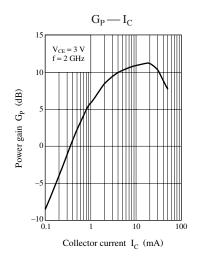


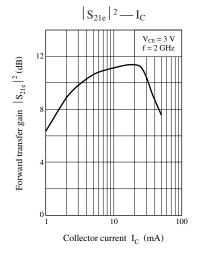


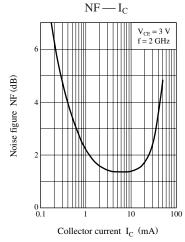


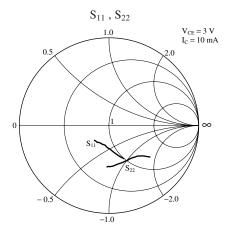


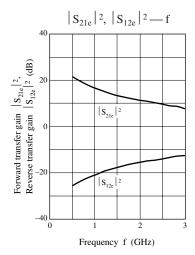












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